

BUK7L3R3-34BRC

N-channel TrenchPLUS standard level FET

Rev. 02 — 26 September 2007

Product data sheet

1. Product profile

1.1 General description

N-channel enhancement mode power Field-Effect Transistor (FET) in a plastic package using NXP High-Performance Automotive (HPA) TrenchMOS technology, featuring very low on-state resistance, internal gate resistor, ElectroStatic Discharge (ESD) protection diodes and clamping diodes that are guaranteed to prevent MOSFET avalanching.

1.2 Features

- Internal gate resistor
- 175 °C rated
- Q101 compliant
- ESD and overvoltage protection

1.3 Applications

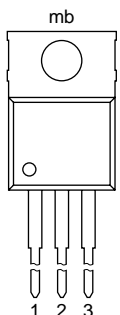
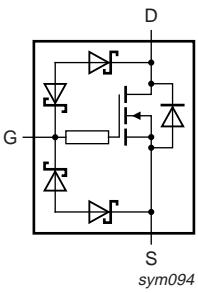
- Automotive systems
- Motors, lamps and solenoids
- General purpose power switching
- 12 V loads

1.4 Quick reference data

- $E_{DS(AL)S} \leq 1.9 \text{ J}$
- $I_D \leq 75 \text{ A}$
- $R_{DS(on)} = 2.9 \text{ m}\Omega$ (typ)
- $P_{tot} \leq 298 \text{ W}$

2. Pinning information

Table 1. Pinning

Pin	Description	Simplified outline	Symbol
1	gate (G)		
2	drain (D)		
3	source (S)		
mb	mounting base; connected to drain (D)		

SOT78C (TO-220)

3. Ordering information

Table 2. Ordering information

Type number	Package		
	Name	Description	Version
BUK7L3R3-34BRC	TO-220	plastic single-ended package; heatsink mounted; 1 mounting hole; 3 leads	SOT78C

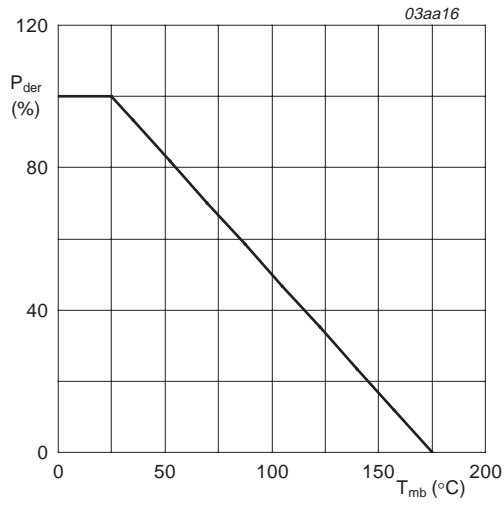
4. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

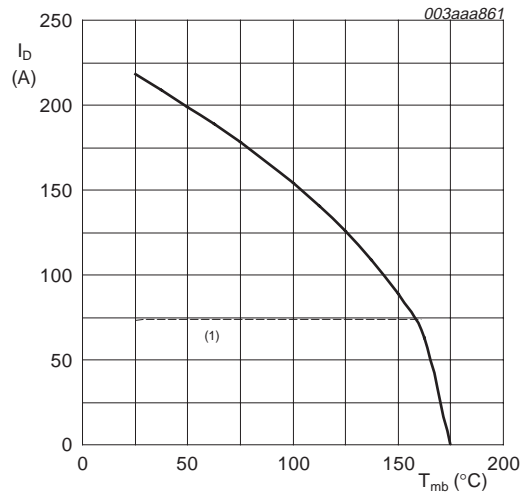
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DS}	drain-source voltage		[1] -	34	V
V_{DGR}	drain-gate voltage (DC)	$R_{GS} = 20 \text{ k}\Omega$	[1] -	34	V
V_{GS}	gate-source voltage		-	± 20	V
I_D	drain current	$T_{mb} = 25 \text{ }^\circ\text{C}$; $V_{GS} = 10 \text{ V}$; see Figure 2 and 3	[2] -	218	A
			[3][4] -	75	A
		$T_{mb} = 100 \text{ }^\circ\text{C}$; $V_{GS} = 10 \text{ V}$; see Figure 2	[3] -	75	A
I_{DM}	peak drain current	$T_{mb} = 25 \text{ }^\circ\text{C}$; pulsed; $t_p \leq 10 \text{ }\mu\text{s}$; see Figure 3	-	872	A
P_{tot}	total power dissipation	$T_{mb} = 25 \text{ }^\circ\text{C}$; see Figure 1	-	298	W
$I_{DG(CL)}$	drain-gate clamping current	$t_p = 5 \text{ ms}$; $\delta = 0.01$	-	50	mA
$I_{GS(CL)}$	gate-source clamping current	continuous	-	10	mA
		$t_p = 5 \text{ ms}$; $\delta = 0.01$	-	50	mA
T_{stg}	storage temperature		-55	+175	$^\circ\text{C}$
T_j	junction temperature		-55	+175	$^\circ\text{C}$
Source-drain diode					
I_{DR}	reverse drain current	$T_{mb} = 25 \text{ }^\circ\text{C}$	[2] -	218	A
			[3][4] -	75	A
I_{DRM}	peak reverse drain current	$T_{mb} = 25 \text{ }^\circ\text{C}$; pulsed; $t_p \leq 10 \text{ }\mu\text{s}$	-	872	A
Avalanche ruggedness					
$E_{DS(AL)S}$	non-repetitive drain-source avalanche energy	unclamped inductive load; $I_D = 75 \text{ A}$; $V_{DS} \leq 34 \text{ V}$; $R_{GS} = 50 \text{ }\Omega$; $V_{GS} = 10 \text{ V}$; starting at $T_j = 25 \text{ }^\circ\text{C}$	-	1.9	J
$E_{DS(AL)R}$	repetitive drain-source avalanche energy		[5] -	-	J
V_{esd}	electrostatic discharge voltage	all pins; human body model; $R = 1.5 \text{ k}\Omega$			
		$C = 100 \text{ pF}$	-	8	kV
		$C = 250 \text{ pF}$	-	8	kV

- [1] Voltage is limited by clamping.
- [2] Current is limited by power dissipation chip rating.
- [3] Continuous current is limited by package.
- [4] Refer to literature 9397 750 12572 for further information.
- [5] Maximum value not quoted. Refer to application note AN10273 for further information.
 - a) Repetitive rating defined in [Figure 14](#).
 - b) Single-pulse avalanche rating limited by a $T_{j(max)}$ of $175 \text{ }^\circ\text{C}$.
 - c) Repetitive avalanche rating limited by an average junction temperature of $170 \text{ }^\circ\text{C}$.



$$P_{der} = \frac{P_{tot}}{P_{tot(25^{\circ}C)}} \times 100\%$$

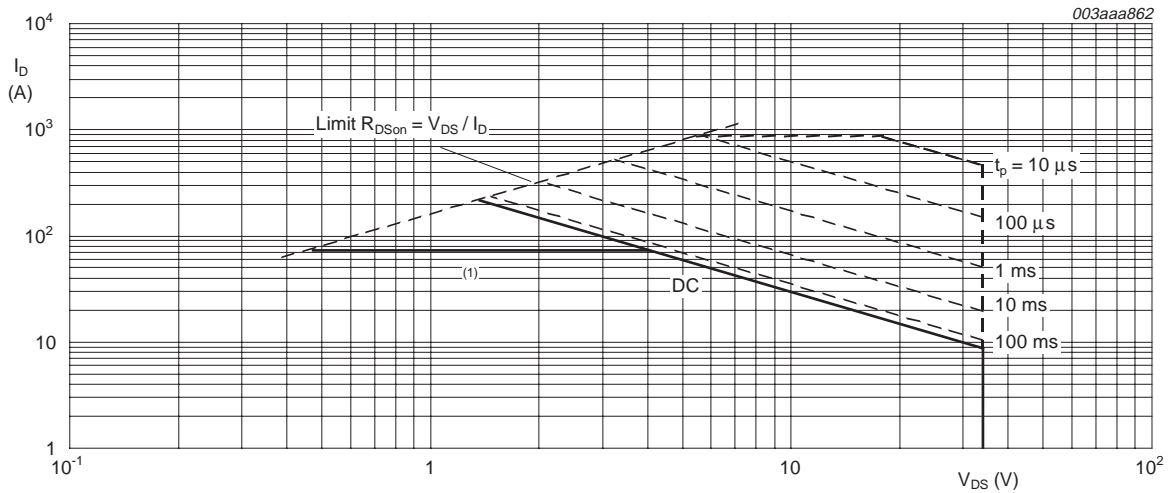
Fig 1. Normalized total power dissipation as a function of mounting base temperature



$V_{GS} \geq 10\text{ V}$

(1) Capped at 75 A due to package

Fig 2. Continuous drain current as a function of mounting base temperature



$T_{mb} = 25^{\circ}C$; I_{DM} is single pulse

(1) Capped at 75 A due to package

Fig 3. Safe operating area; continuous and peak drain currents as a function of drain-source voltage

5. Thermal characteristics

Table 4. Thermal characteristics

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$R_{th(j-a)}$	thermal resistance from junction to ambient		-	60	-	K/W
$R_{th(j-mb)}$	thermal resistance from junction to mounting base		-	-	0.5	K/W

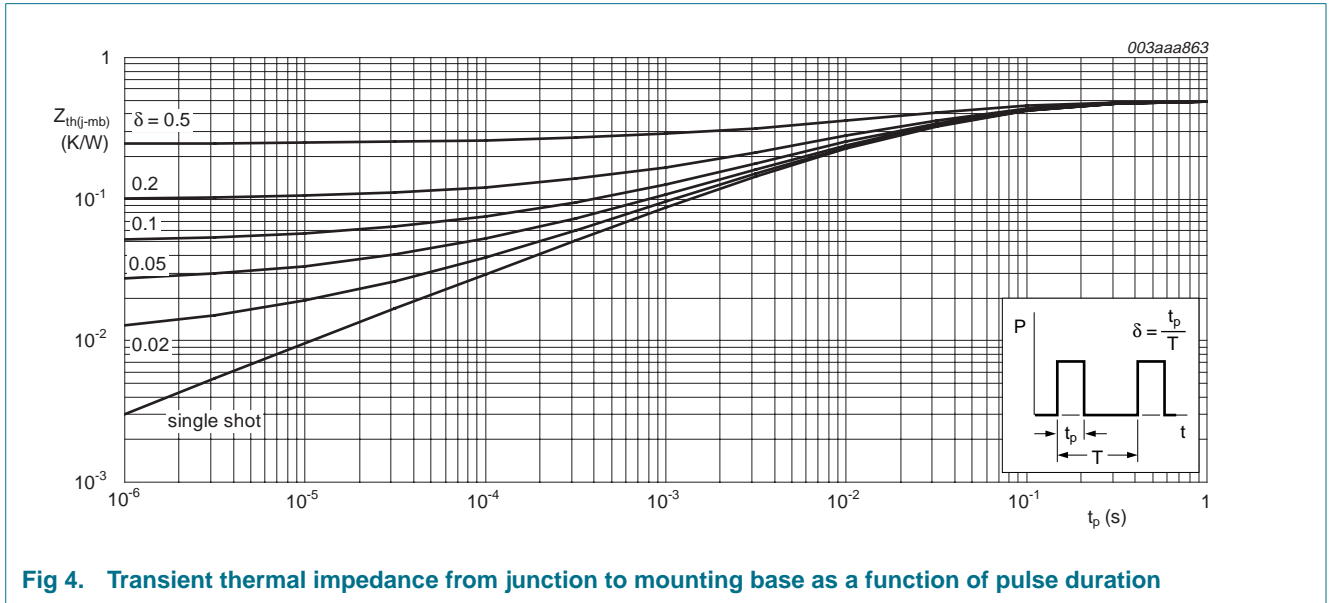


Fig 4. Transient thermal impedance from junction to mounting base as a function of pulse duration

6. Characteristics

Table 5. Characteristics

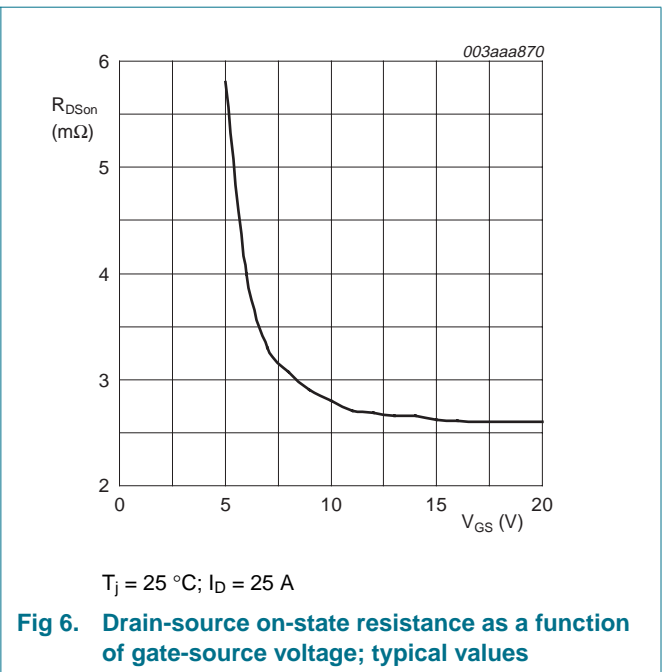
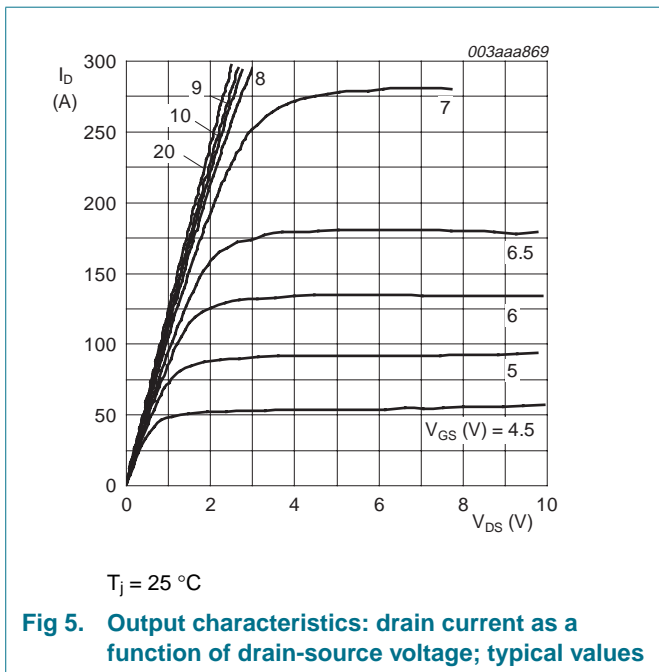
$T_j = 25\text{ °C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit	
Static characteristics							
$V_{(BR)DG}$	drain-gate breakdown voltage	$I_D = 2\text{ mA}; V_{GS} = 0\text{ V}$					
		$T_j = 25\text{ °C}$	34	-	45	V	
		$T_j = -55\text{ °C}$	34	-	45	V	
$V_{DS(CL)}$	drain-source clamping voltage	$I_{GD(CL)} = -2\text{ mA}; I_D = 1\text{ A}$; see Figure 17 and 18	-	41	-	V	
$V_{GS(th)}$	gate-source threshold voltage	$I_D = 1\text{ mA}; V_{DS} = V_{GS}$; see Figure 9 and 10					
		$T_j = 25\text{ °C}$	2	3	4	V	
		$T_j = 175\text{ °C}$	1	-	-	V	
		$T_j = -55\text{ °C}$	-	-	4.4	V	
I_{DSS}	drain leakage current	$V_{DS} = 16\text{ V}; V_{GS} = 0\text{ V}$					
		$T_j = 25\text{ °C}$	-	0.1	0.6	μA	
		$T_j = 150\text{ °C}$	-	5	50	μA	
		$T_j = 175\text{ °C}$	-	30	250	μA	
$V_{(BR)GSS}$	gate-source breakdown voltage	$I_G = \pm 1\text{ mA}; -55\text{ °C} < T_j < +175\text{ °C}$	20	22	-	V	
I_{GSS}	gate leakage current	$V_{GS} = \pm 10\text{ V}; V_{DS} = 0\text{ V}$					
		$T_j = 25\text{ °C}$	-	5	1000	nA	
		$T_j = 175\text{ °C}$	-	-	50	μA	
		$V_{GS} = \pm 16\text{ V}; V_{DS} = 0\text{ V}$					
		$T_j = 175\text{ °C}$	-	-	150	μA	
R_{DSon}	drain-source on-state resistance	$V_{GS} = 10\text{ V}; I_D = 25\text{ A}$; see Figure 7 and 8					
		$T_j = 25\text{ °C}$	[1]	-	2.9	3.3	$\text{m}\Omega$
		$T_j = 175\text{ °C}$	-	-	6.3	$\text{m}\Omega$	
R_G	gate resistance		-	11	-	Ω	

Table 5. Characteristics ...continued
 $T_j = 25\text{ }^\circ\text{C}$ unless otherwise specified.

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
Dynamic characteristics						
$Q_{G(\text{tot})}$	total gate charge	$I_D = 25\text{ A}$; $V_{DS} = 27\text{ V}$; $V_{GS} = 10\text{ V}$; see Figure 12	-	109	-	nC
Q_{GS}	gate-source charge		-	22	-	nC
Q_{GD}	gate-drain charge		-	55	-	nC
C_{iss}	input capacitance	$V_{GS} = 0\text{ V}$; $V_{DS} = 25\text{ V}$; $f = 1\text{ MHz}$; see Figure 16	-	5050	6730	pF
C_{oss}	output capacitance		-	1300	1560	pF
C_{riss}	reverse transfer capacitance		-	510	690	pF
$t_{d(\text{on})}$	turn-on delay time	$V_{DS} = 30\text{ V}$; $R_L = 1.2\text{ }\Omega$; $V_{GS} = 10\text{ V}$; $R_G = 10\text{ }\Omega$	-	69	-	ns
t_r	rise time		-	150	-	ns
$t_{d(\text{off})}$	turn-off delay time		-	290	-	ns
t_f	fall time		-	210	-	ns
L_D	internal drain inductance	measure from drain lead 6 mm from package to center of die	-	4.5	-	nH
		measure from contact screw on mounting base to center of die	-	3.5	-	nH
L_S	internal source inductance	measure from source lead from package to source bonding pad	-	7.5	-	nH
Source-drain diode						
V_{SD}	source-drain voltage	$I_S = 25\text{ A}$; $V_{GS} = 0\text{ V}$; see Figure 13	-	0.85	1.2	V
t_{rr}	reverse recovery time	$I_S = 20\text{ A}$; $di_S/dt = -100\text{ A}/\mu\text{s}$;	-	93	-	ns
Q_r	recovered charge	$V_{GS} = 0\text{ V}$; $V_R = 30\text{ V}$	-	65	-	nC

[1] R_{DSon} measured at 1.5 mm away from the plastic body.



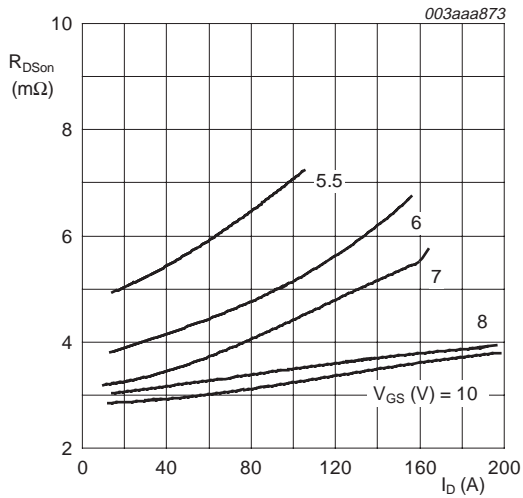
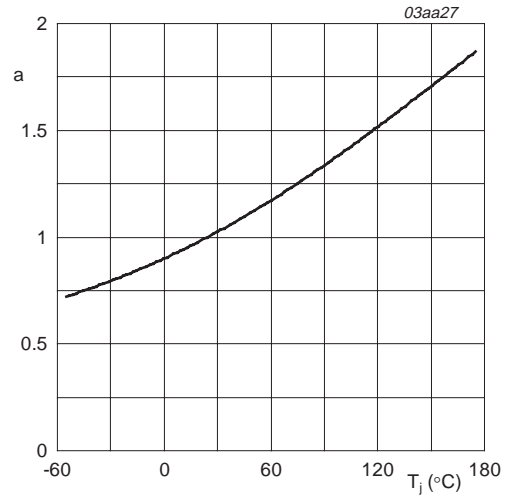
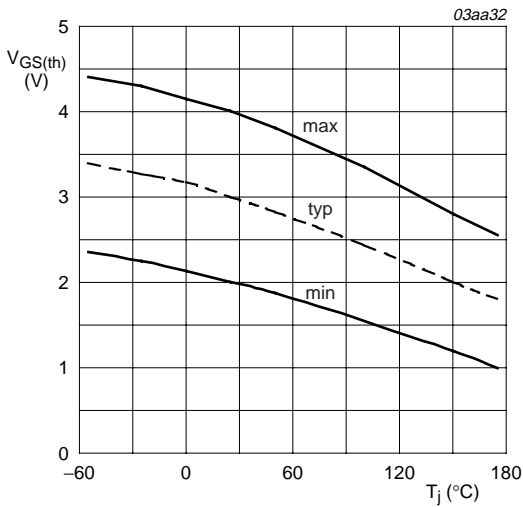


Fig 7. Drain-source on-state resistance as a function of drain current; typical values



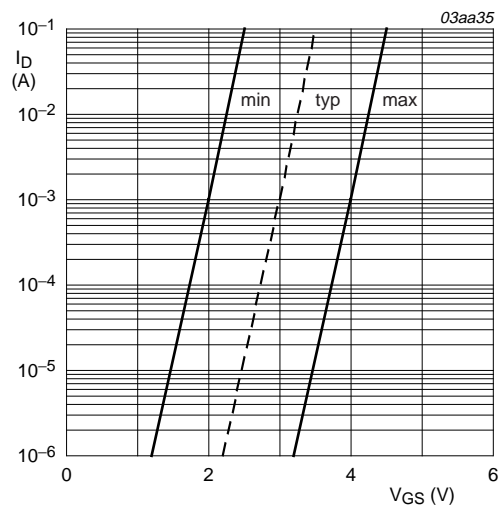
$$a = \frac{R_{DS(on)}}{R_{DS(on)(25^\circ C)}}$$

Fig 8. Normalized drain-source on-state resistance factor as a function of junction temperature



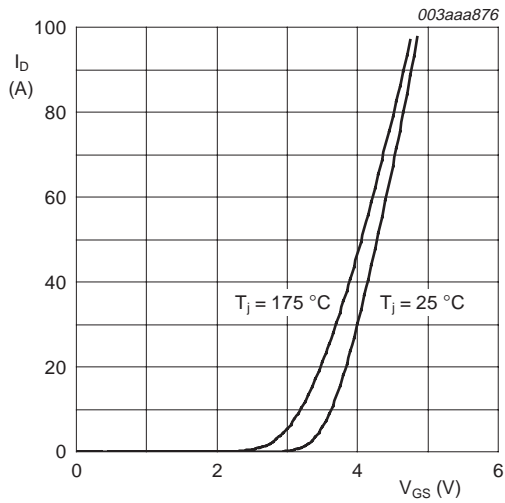
$I_D = 1 \text{ mA}; V_{DS} = V_{GS}$

Fig 9. Gate-source threshold voltage as a function of junction temperature



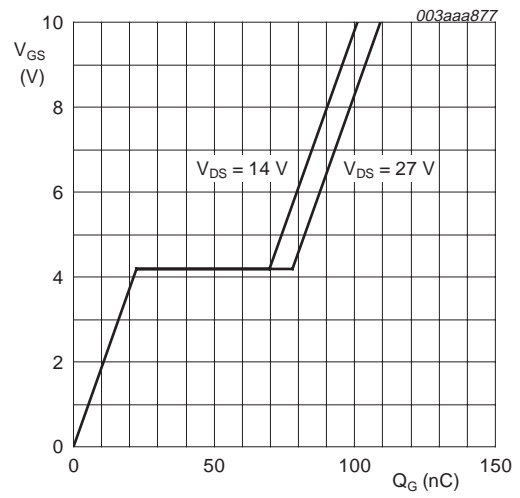
$T_j = 25^\circ C; V_{DS} = V_{GS}$

Fig 10. Sub-threshold drain current as a function of gate-source voltage



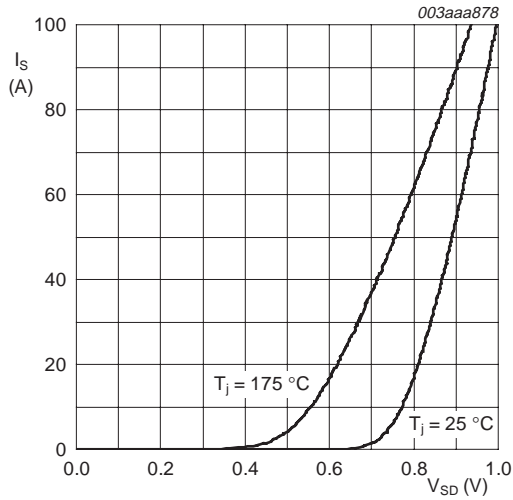
$V_{DS} = 25\text{ V}$

Fig 11. Transfer characteristics: drain current as a function of gate-source voltage; typical values



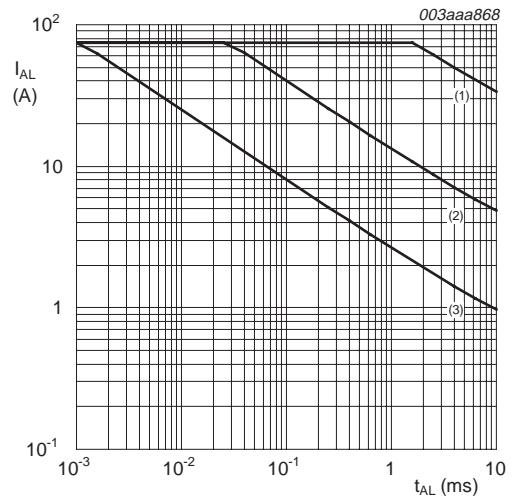
$T_j = 25\text{ °C}; I_D = 25\text{ A}$

Fig 12. Gate-source voltage as a function of gate charge; typical values



$V_{GS} = 0\text{ V}$

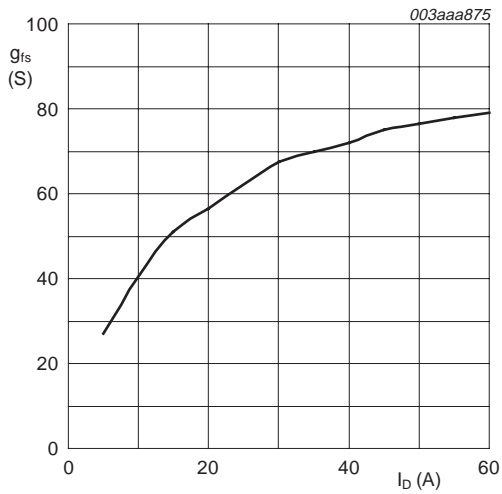
Fig 13. Source (diode forward) current as a function of source-drain (diode forward) voltage; typical values



See [Table note 5](#) of [Table 3](#) "Limiting values".

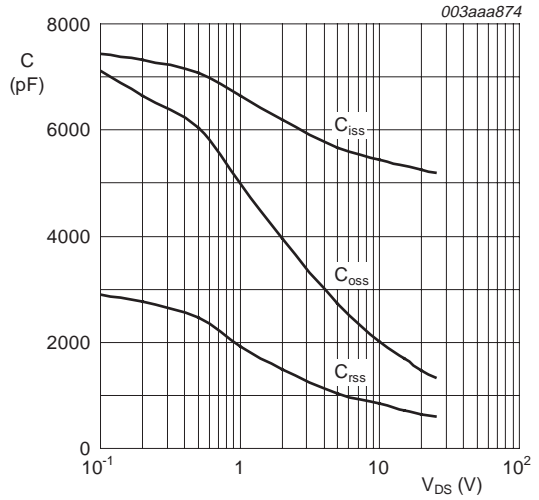
- (1) Single-pulse; $T_j = 25\text{ °C}$
- (2) Single-pulse; $T_j = 150\text{ °C}$
- (3) Repetitive

Fig 14. Single-pulse and repetitive avalanche rating; avalanche current as a function of avalanche time



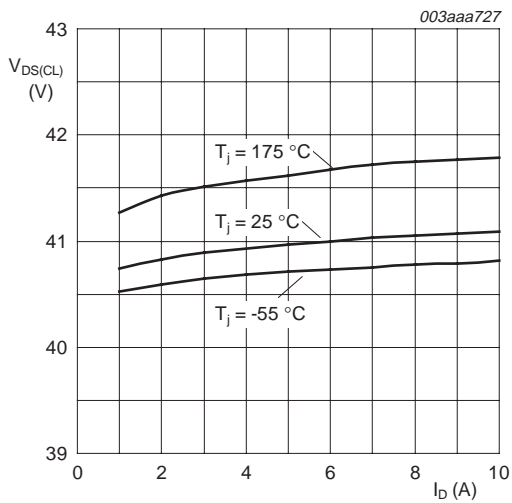
$T_j = 25\text{ }^\circ\text{C}; V_{DS} = 25\text{ V}$

Fig 15. Forward transconductance as a function of drain current; typical values



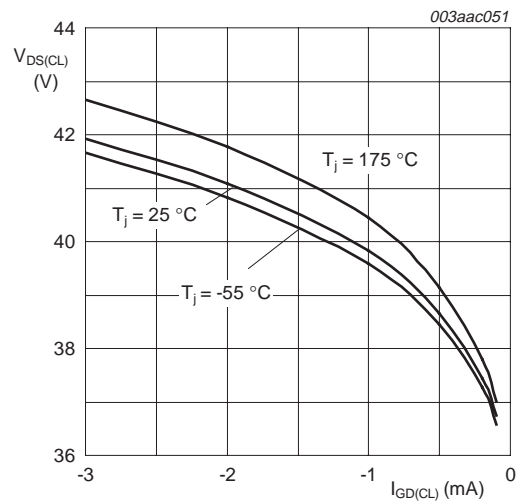
$V_{GS} = 0\text{ V}; f = 1\text{ MHz}$

Fig 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



$I_{GD(CL)} = -2\text{ mA}$

Fig 17. Drain-source clamping voltage as a function of drain current; typical values



$I_D = 10\text{ A}$

Fig 18. Drain-source clamping voltage as a function of gate-drain clamping current; typical values

7. Package outline

Plastic single-ended package; heatsink mounted; 1 mounting hole; 3 leads

SOT78C

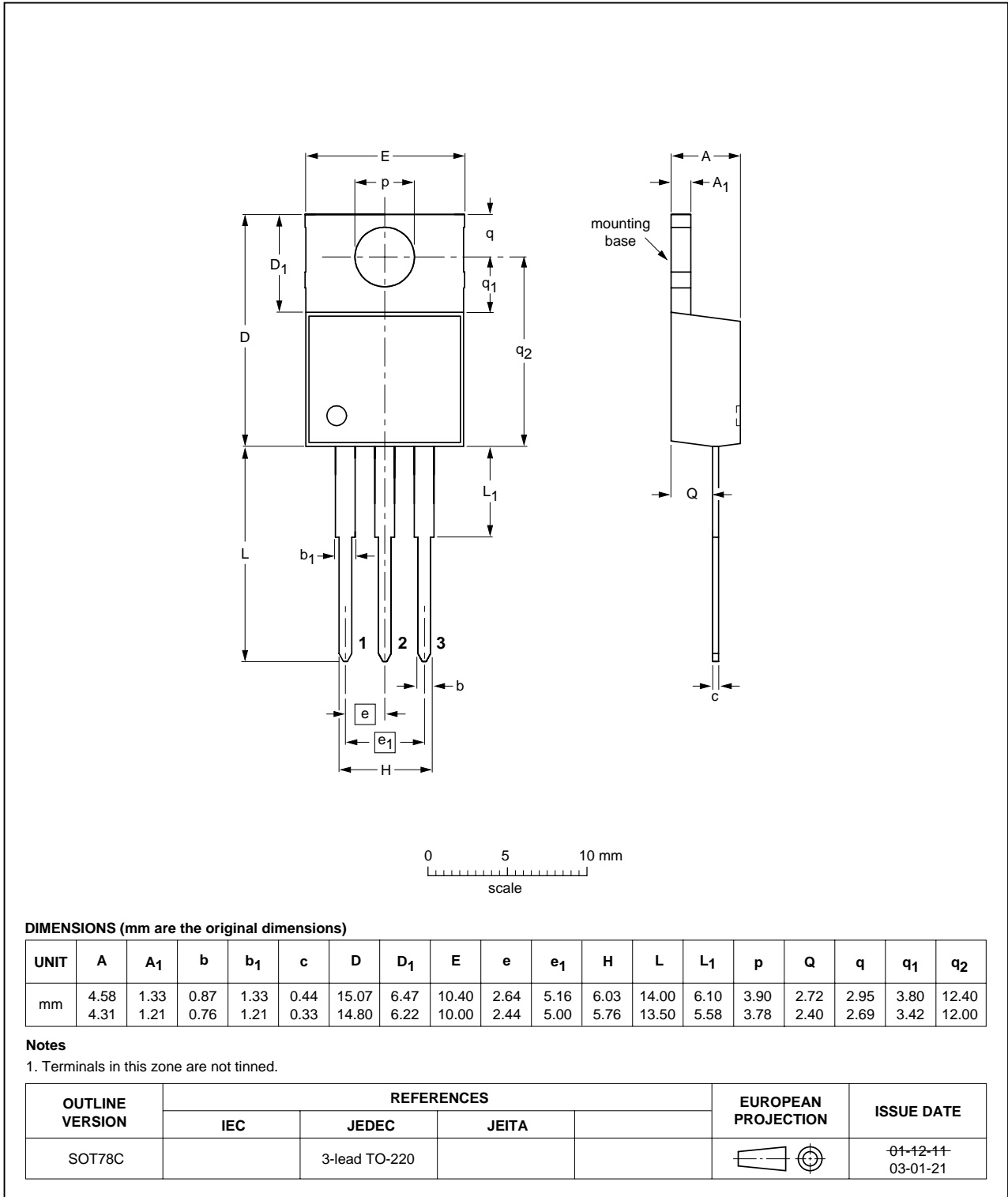


Fig 19. Package outline SOT78C (TO-220)

8. Revision history

Table 6. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
BUK7L3R3-34BRC_2	20070926	Product data sheet	-	BUK7L3R3-34BRC_1
Modifications:	<ul style="list-style-type: none">• Table 5: updated maximum value of drain leakage current• Table 5: added Table note 1			
BUK7L3R3-34BRC_1	20070515	Product data sheet	-	-

9. Legal information

9.1 Data sheet status

Document status ^{[1][2]}	Product status ^[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

[1] Please consult the most recently issued document before initiating or completing a design.

[2] The term 'short data sheet' is explained in section "Definitions".

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Date of release: 26 September 2007

Document identifier: BUK7L3R3-34BRC_2